



THE DATASHEET OF NTMS4873NFR2G

NTMS4873NF

Power MOSFET

30 V, 11.5 A, N-Channel, SO-8

Features

- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Includes SyncFET Schottky Diode
- Optimized Gate Charge to Minimize Switching Losses
- SOIC-8 Surface Mount Package Saves Board Space
- This is a Pb-Free Device

Applications

- Synchronous FET for DC-DC Converters
- Low Side Notebook Non-VCORE Converters

MAXIMUM RATINGS ($T_J = 25^\circ\text{C}$ unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	± 20	V
Continuous Drain Current $R_{\theta JA}$ (Note 1)	Steady State	$T_A = 25^{\circ}\text{C}$	I_D	8.9	A
		$T_A = 70^{\circ}\text{C}$		7.2	
Power Dissipation $R_{\theta JA}$ (Note 1)		$T_A = 25^{\circ}\text{C}$	P_D	1.39	W
Continuous Drain Current $R_{\theta JA}$ (Note 2)		$T_A = 25^{\circ}\text{C}$	I_D	7.1	A
		$T_A = 70^{\circ}\text{C}$		5.7	
Power Dissipation $R_{\theta JA}$ (Note 2)		$T_A = 25^{\circ}\text{C}$	P_D	0.87	W
Continuous Drain Current $R_{\theta JA}$, $t \leq 10$ s (Note 1)		$T_A = 25^{\circ}\text{C}$	I_D	11.5	A
		$T_A = 70^{\circ}\text{C}$		9.2	
Power Dissipation $R_{\theta JA}$, $t \leq 10$ s (Note 1)		$T_A = 25^{\circ}\text{C}$	P_D	2.31	W
Pulsed Drain Current	$T_A = 25^{\circ}\text{C}$, $t_p = 10 \mu\text{s}$		I_{DM}	56	A
Operating Junction and Storage Temperature			T_J , T_{stg}	-55 to 150	$^{\circ}\text{C}$
Source Current (Body Diode)			I_S	3.3	A
Single Pulse Drain-to-Source Avalanche Energy ($T_J = 25^{\circ}\text{C}$, $V_{DD} = 30$ V, $V_{GS} = 10$ V, $I_L = 11$ A _{pk} , $L = 1$ mH, $R_G = 25 \Omega$)			E_{AS}	60.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T_L	260	$^{\circ}\text{C}$

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient – Steady State (Note 1)	$R_{\theta JA}$	89.9	$^\circ\text{C/W}$
Junction-to-Ambient – $t \leq 10$ s (Note 1)	$R_{\theta JA}$	54.2	
Junction-to-Foot (Drain)	$R_{\theta JF}$	35.6	
Junction-to-Ambient – Steady State (Note 2)	$R_{\theta JA}$	143	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. Surfacemounted on FR4 board using 1 sq-in pad, 2 oz Cu.
2. Surfacemounted on FR4 board using the minimum recommended pad size.

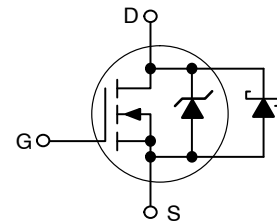


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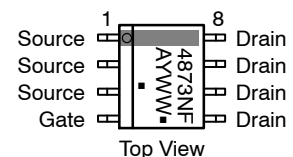
$V_{(BR)DSS}$	$R_{DS(ON)} \text{ MAX}$	$I_D \text{ MAX}$
30 V	12 m Ω @ 10 V	11.5 A
	15 m Ω @ 4.5 V	

N-Channel



SO-8
CASE 751
STYLE 12

MARKING DIAGRAM/ PIN ASSIGNMENT



4873NF = Device Code

A = Assembly Location

Y = Year

WW = Work Week

▪ = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping†
NTMS4873NFR2G	SO-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

NTMS4873NF

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
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OFF CHARACTERISTICS

Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J			10		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V, T _J = 25°C			250	μA
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V			±100	nA

ON CHARACTERISTICS (Note 3)

Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 250 μA	1.45		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J			6		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 10 A		9	12	mΩ
		V _{GS} = 4.5 V, I _D = 8.5 A		12	15	
Forward Transconductance	g _{FS}	V _{DS} = 1.5 V, I _D = 10 A		22		S

CHARGES, CAPACITANCES AND GATE RESISTANCE

Input Capacitance	C _{iss}	V _{GS} = 0 V, f = 1.0 MHz, V _{DS} = 15 V		1275	1900	pF
Output Capacitance	C _{oss}			345	525	
Reverse Transfer Capacitance	C _{rss}			145	225	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 10 A		10.5	16	nC
Threshold Gate Charge	Q _{G(TH)}			1.3		
Gate-to-Source Charge	Q _{GS}			3.7	6.0	
Gate-to-Drain Charge	Q _{GD}			3.9	6.5	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 10 A		21.4	32	nC

SWITCHING CHARACTERISTICS (Note 4)

Turn-On Delay Time	t _{d(on)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 1.0 A, R _G = 6.0 Ω		9.8	16	ns
Rise Time	t _r			3.8	7.0	
Turn-Off Delay Time	t _{d(off)}			22.3	45	
Fall Time	t _f			14.3	25	

DRAIN-SOURCE DIODE CHARACTERISTICS

Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 3.5 A	T _J = 25°C		0.55	0.7	V
			T _J = 125°C		0.5		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dI _S /dt = 100 A/μs, I _S = 10 A			20	35	ns
Charge Time	t _a				9.5	15	
Discharge Time	t _b				10.6	20	
Reverse Recovery Charge	Q _{RR}				9.0	14	nC

PACKAGE PARASITIC VALUES

Source Inductance	L _S	T _A = 25°C		0.66		nH
Drain Inductance	L _D			0.20		nH
Gate Inductance	L _G			1.5		nH
Gate Resistance	R _G			1.5	3.0	Ω

3. Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.

4. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

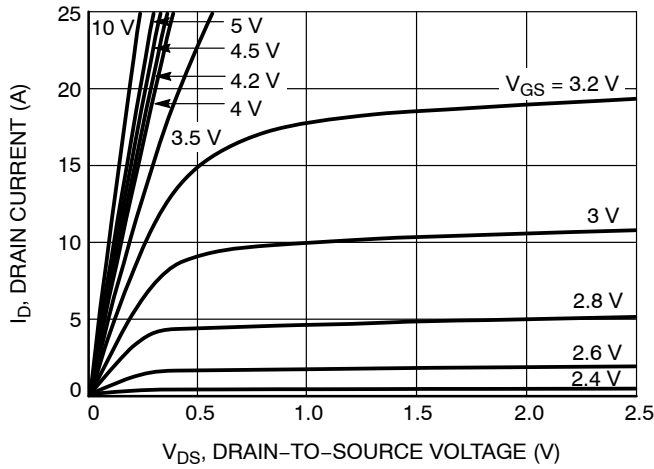


Figure 1. On-Region Characteristics

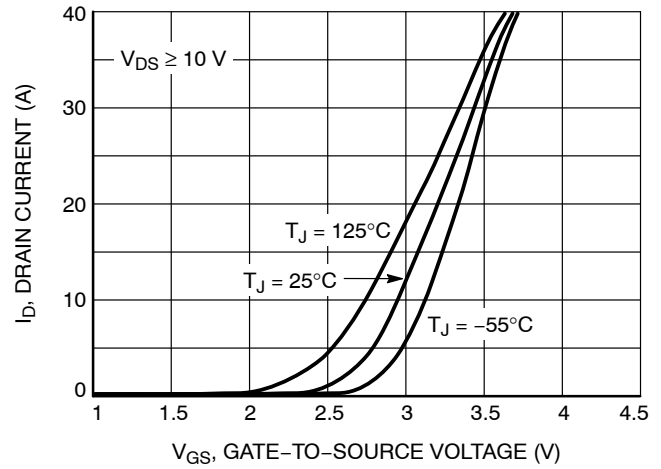


Figure 2. Transfer Characteristics

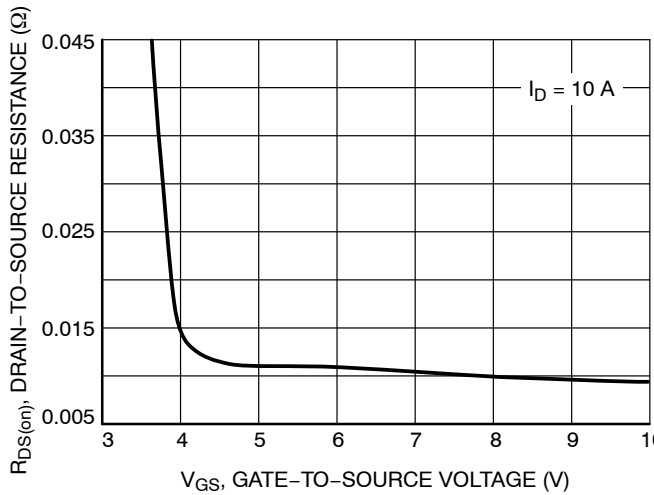


Figure 3. On-Resistance vs. Gate-to-Source Voltage

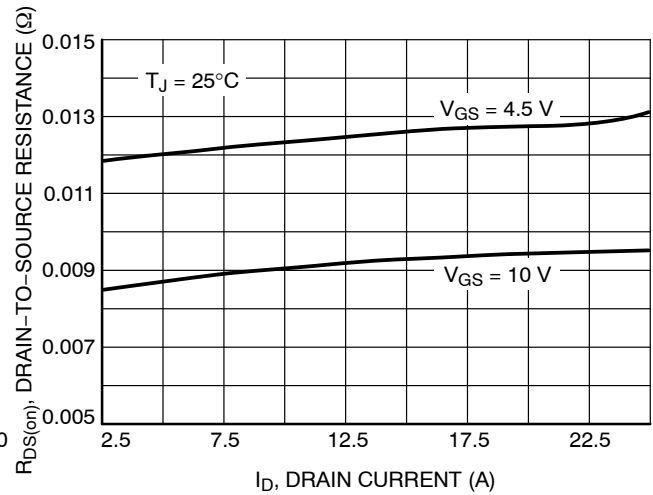


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

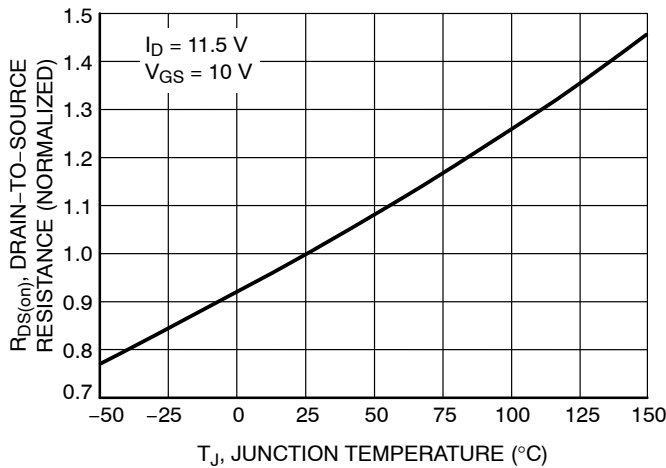


Figure 5. On-Resistance Variation with Temperature

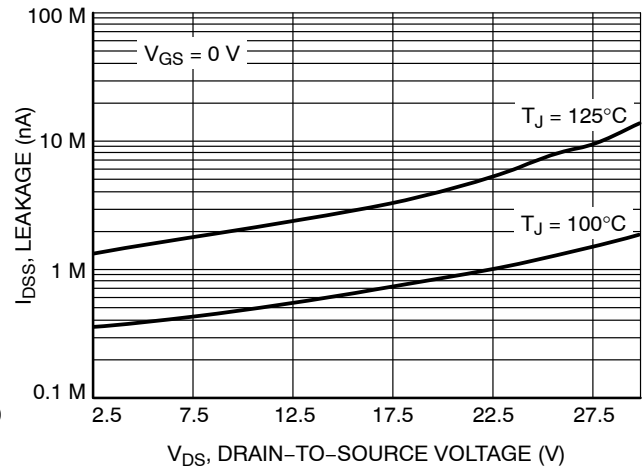


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

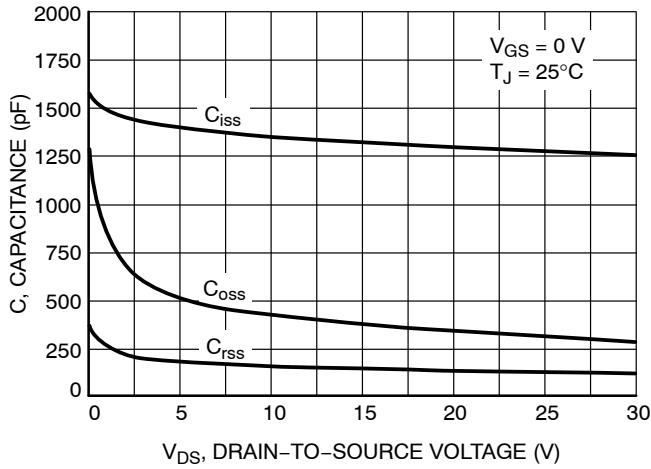


Figure 7. Capacitance Variation

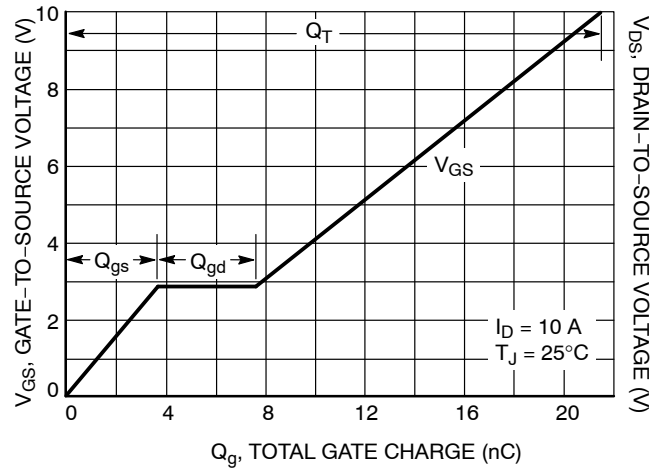


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

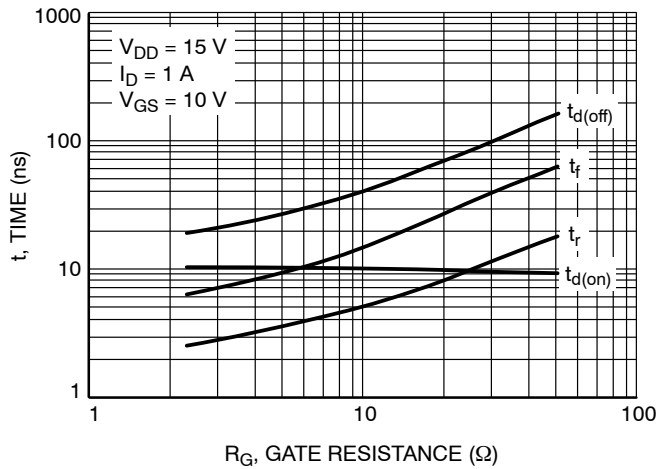


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

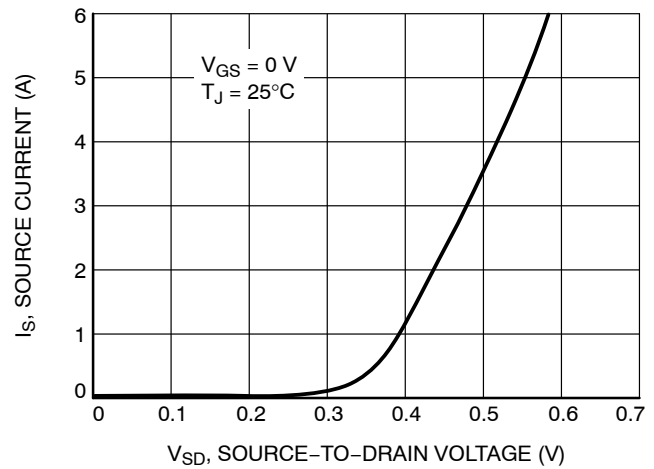


Figure 10. Diode Forward Voltage vs. Current

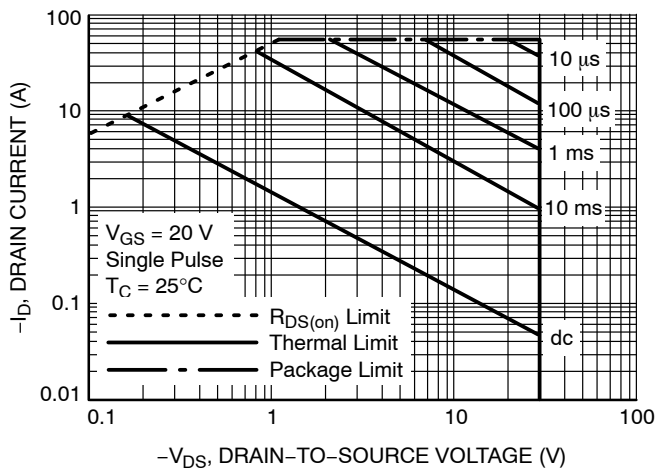


Figure 11. Maximum Rated Forward Biased Safe Operating Area

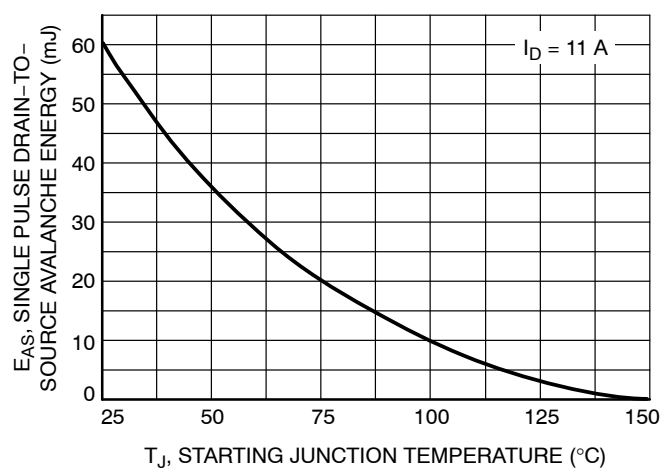


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

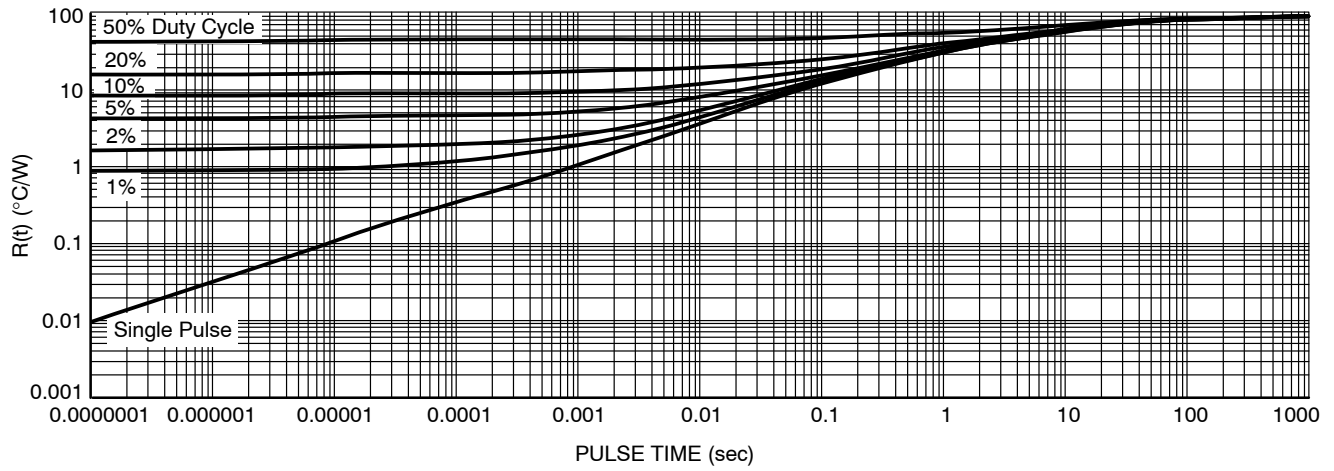


Figure 13. Thermal Response – $R_{\theta JA}$ at Steady State (1 inch sq pad)

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